# Structural Monitoring Using Advanced NDT Techniques: Volume II

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Deadline for manuscript submissions:
**closed (20 June 2024)**

## Message from the Guest Editors

Dear Colleagues,

Advanced NDT (nondestructive testing) techniques are excellent tools for safely maintaining structures, such as bridges, tunnels and buildings, as well as cars, airplanes, ships, etc. Over the course of several decades, NDT techniques were developed to be more precise and automatic, including data-driven artificial intelligence, replacing conventional techniques based on human experience. Advanced NDT techniques can involve many methods, such as holography, shearography, speckle photography, ESPI, etc., with these techniques now being developed for application in the evaluation of materials and structural statuses.

This second Special Issue of Applied Science, "The Second Version of Structural Monitoring Using Advanced NDT Techniques", aims to provide recent achievements in structural monitoring and materials characterization using advanced NDT techniques and data-driven AI.

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mdpi.com/si/142265

Special Issue

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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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